

Application/Control No.	Applicant(s)/Patent under Reexamination NISHIYAMA ET AL.	
10/669,320		
Examiner	Art Unit	
Kenneth A. Parker	2871	

	SEARCHED				
Class	Subclass	Date	Examiner		
349	139	6/21/2005	КР <u>Л</u>		
:	143	6/21/2005			
	129	6/21/2005			
	144	6/24/2005	\prod_{Λ}		
7	84	6/21/2005	V		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	<u> </u>			

SEARCH NO (INCLUDING SEARCH	STRATEGY	<u></u>
	DATE	EXMR
	,	
•		
*		
·		